

Test item list

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Test Configuration:

Num	Item	Spec
1.	Operator Panel:	TF-ONYX-174HT-A1-1110
	1.LCD	17" CPT CLAA170EA07
	2. Power Supply	Astordyne ASM-150-24
	4. Inverter	HWA YOUN QF132v1.16
2.	CPU Board:	EMB-852T Rev: A1.1
	1. Bios Ver.	ONYX-174 A0.2
	2.CPU	Intel Pentium-M Processor 1.6GHz
	3.Memory	DSL 512MB / Hynix HY5DU121622CTP-J
	4. HDD	FUJITSU MHW2040AT / 40GB
	5.Test Software	Windows XP / Run PassMark Burn In Test 5.1 Pro

CPU Cooler



Temperature cycle test

Test Date: 05-23~26-2008

Test Product: ONYX-174

Test Site: AAEON QA Internal Lab.

Performed By: Rex Chang

Test Standard: Reference IEC68-2-14 Testing procedures
Test N: Change of temperature Test

Test Equipment:

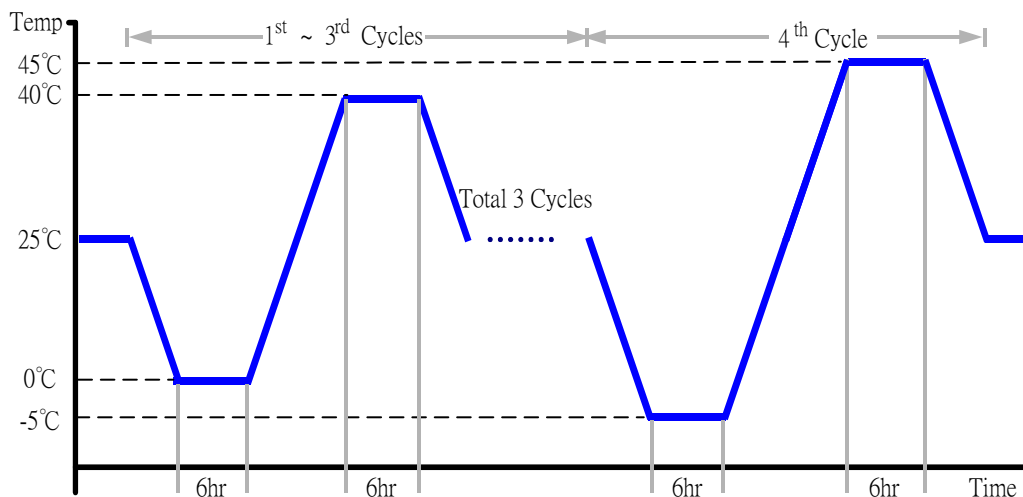
Programmable Temperature & Humidity Chamber
K.SON. INS. TECH. CORP.
Model: THS-D4H+-100
Date of Calibration: 05/12/08
Serial Number: 1241

Temperature Measurement:

40 Channel Thermal Recorder:
YOKOGAWA Inc,
Model: DA100-13-1D
Date of Calibration: 12/13/07
Serial Number: 12A323190

Test Condition:

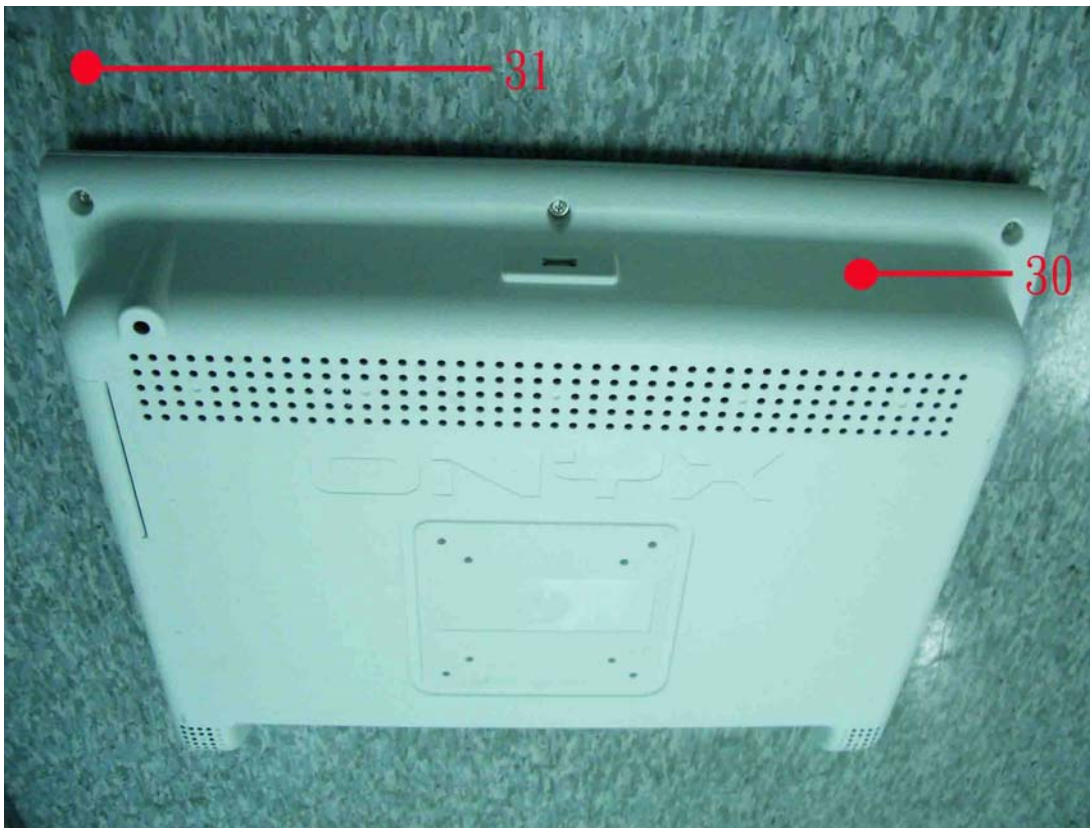
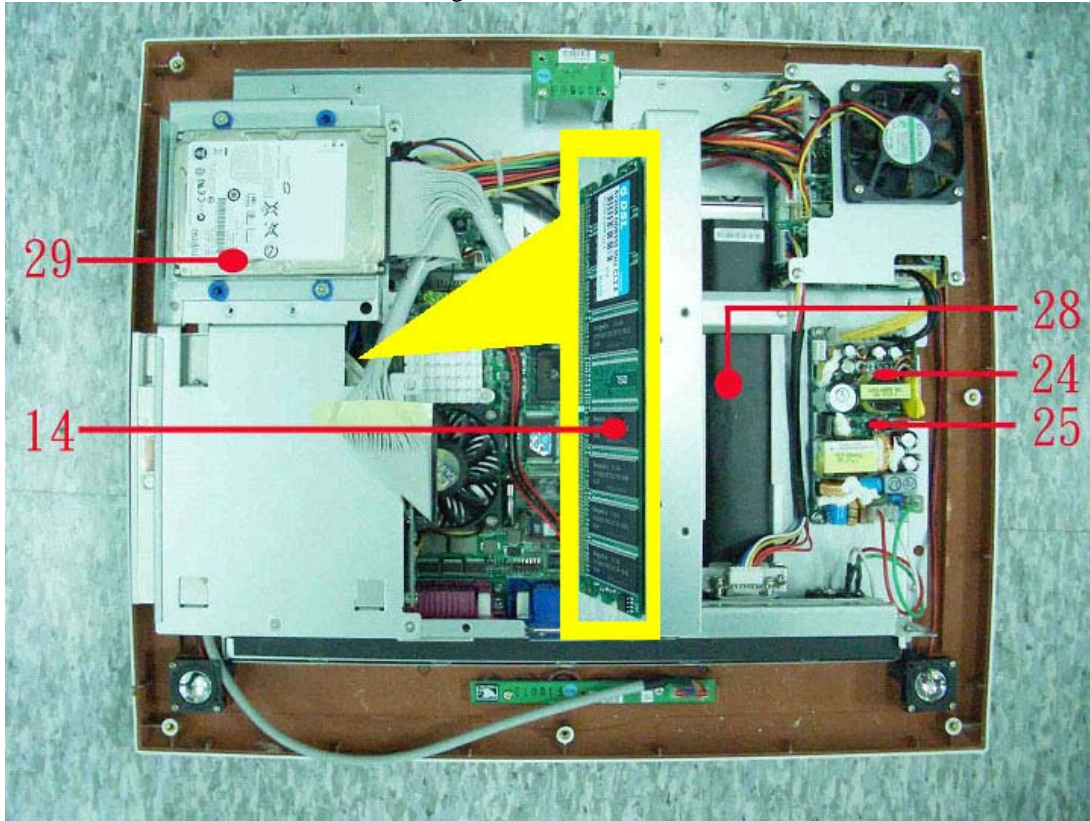
1. Test Low Temperature: 0°C (1~3 cycles)
-5°C (4th cycle)
2. Test High Temperature: 40°C (1~3 cycles)
45°C (4th cycle)
3. Test dwell time: 6Hrs
4. Temperature slope: 2°C/min
5. Test cycle: 4 cycles
6. Test Environment Curve:



Temperature cycle test

Terminal Recorder:

Measuring Accelerometer Position



Temperature cycle test

Thermal profile data:

ONYX-174

Point	Temp. Stage(°C)	Spec	40	25	0
EMB-852T					
01. CPU		100	77.4	62.4	37.4
02. U24-Chipset.NB82852GM.Intel.RG82852GM		105	76.1	61.1	36.1
03. U25-Chipset ICH4.INTEL.FW82801DB		110	74.7	59.7	34.7
04. U54-ACPI Power Controller.Intersil.ISL6506BCB		100	72.4	57.4	32.4
05. U10-N-Channel.30V.10A.13.5mΩ .MOSFET.APEC.AP4410M		125	72.2	57.2	32.2
06. L2- INDUCTOR.3.3uH.20%. VISHAY.IHLP2525CZRZ3R3M01		125	73.2	58.2	33.2
07. U11-Step-Down DC/DC Controller.Anpec.APW7057		100	74.0	59.0	34.0
08. U57-(TF)RS232 Driver ESD 15KV.INTERASIL.HIN213ECAZ		70	69.9	54.9	29.9
09. U22-CLOCK GENERATOR.ICS.ICS952601		115	77.6	62.6	37.6
10. U45-(TF)RS232 Driver ESD 15KV.INTERASIL.HIN213ECAZ		70	69.9	54.9	29.9
11. U44-(TF)RS232 Driver ESD 15KV.INTERASIL.HIN213ECAZ		70	66.9	51.9	26.9
12. TC25-220uF.2V.Panasonic.EEFSX0D221YR		105	63.4	48.4	23.4
13. TC27-150uF.6.3V.Panasonic.ECGUD0J151R		105	68.2	53.2	28.2
14. Memory		70	66.1	51.1	26.1
PER-P12D A02					
15. L2 - (TF)COIL.3.3uH.GOTREND.GSTC135P-3R3MF		125	86.6	71.6	46.6
16. L3 - (TF)COIL.2.2uH.GOTREND.GSTC135P-2R2MF		125	87.0	72.0	47.0
17. U4 - (TF) Regulator.Vin 3.5-36V.LINEAR.LTC3728EUH#PBF		85	79.8	64.8	39.8
18. L7 - (TF)COIL.33uH.GOTREND.GDO-0804-P-330-M		85	63.1	48.1	23.1
19. D11 - (TF) D Schottky.60V.3A.SMD.WILLAS.SK36C-TG		125	63.1	48.1	23.1
20. T2 - (TF)POWER MOSFET.SMD.SO-8.International Rectifier.IRF7416PbF		125	64.1	49.1	24.1
21. U6 - (TF) Lithium-Ion Battery.Charger.LINEAR.LTC4007EGN#PBF		85	66.5	51.5	26.5
22. T3 - (TF)POWER MOSFET.SMD.SO-8.International Rectifier.IRF7416PbF		125	65.7	50.7	25.7
23. D10 - (TF)D Schottky.SMC.Power Rectifier.ON.MBRS330T3G		100	76.9	61.9	36.9
Power					
24. T1		105	77.9	62.9	37.9
25. Q5		125	95.7	80.7	55.7
Inverter					
26. IC1		85	68.1	53.1	28.1
27. Q2		150	66.3	51.3	26.3
28. Battery		55	58.6	43.6	18.6
29. HDD		60	56.3	41.3	16.3
30. Control Box Surface		N/A	51.9	36.9	11.9
31. Chamber Air Temperature		N/A	41.0	26.0	1.0

Temperature cycle test

Sample Configuration & Quantity Under Test:

Quantity: 1 (ONYX-174)

Test Result:

No problem was found during the temperature operation cycle test.

Test Date: 05-19~21-2008

Test Product: ONYX-174

Test Site: AAEON QA Internal Lab.

Performed By: Rex Chang

Test Standard: Reference IEC 68-2-2 Testing procedures
Test Bb: Dry Heat Test (Non-operation)

Test Equipment:

Programmable Temperature & Humidity Chamber
K.SON. INS. TECH. CORP.
Model: THS-D4H+-100
Date of Calibration: 05/12/08
Serial Number: 1241

Testing Item:

1. Test Temperature: 60°C
2. Test Times: 48Hrs
3. Test Software: Windows XP / Run PassMark Burn In Test 5.1 Pro
4. Test Environment Curve:



Sample Configuration & Quantity Under Test:

Quantity: 1 (ONYX-174)

Test Result:

No problem was found after the high temperature storage test.

Low temperature storage test

Test Date: 05-16~19-2008

Test Product: ONYX-174

Test Site: AAEON QA Internal Lab.

Performed By: Rex Chang

Test Standard: Reference IEC 68-2-1 Testing procedures
Test Ab: Cold Test (Non-operation)

Test Equipment:

Programmable Temperature & Humidity Chamber
K.SON. INS. TECH. CORP.
Model: THS-D4H+-100
Date of Calibration: 05/12/08
Serial Number: 1241

Testing Item:

1. Test Temperature: -20°C
2. Test Times: 48Hrs
3. Test Software: Windows XP / Run PassMark Burn In Test 5.1 Pro
4. Test Environment Curve:



Sample Configuration & Quantity Under Test:
Quantity: 1 (ONYX-174)

Test Result:

No problem was found after the low temperature storage test.

Test Date: 05-12~15-2008

Test Product: ONYX-174

Test Site: AAEON QA Internal Lab.

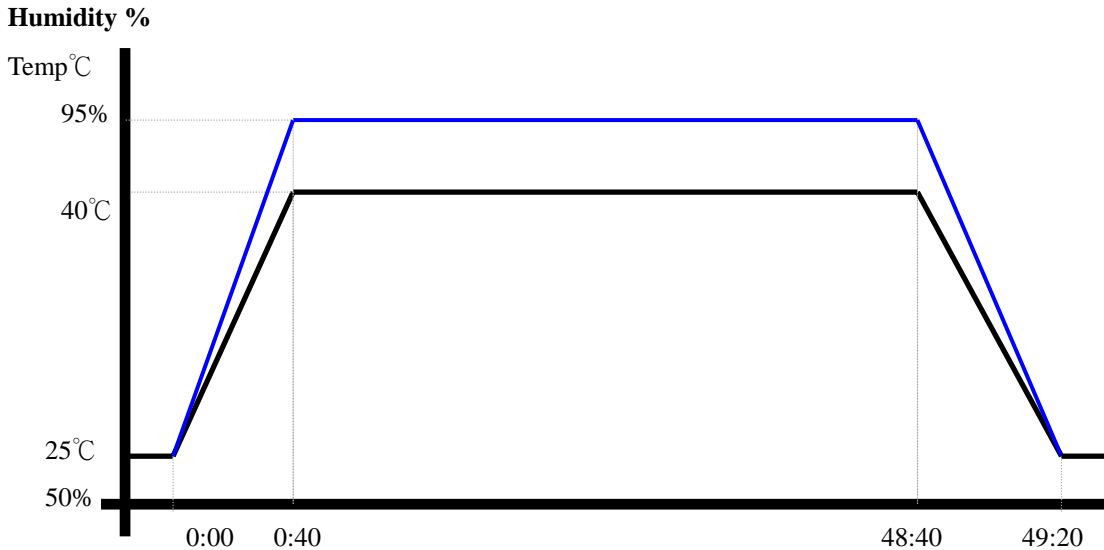
Performed By: Rex Chang

Test Standard: Reference IEC 68-2-3 Testing procedures
Test Ca: Damp heat, steady state (Non-operation)

Test Equipment:
Programmable Temperature & Humidity Chamber
K.SON. INS. TECH. CORP.
Model: THS-D4H+-100
Date of Calibration: 05/12/08
Serial Number: 1241

Testing Item:

1. Test Temperature: 40°C
2. Test Humidity: 95%RH
3. Test Times: 48Hrs
4. Test Software: Windows XP / Run PassMark Burn In Test 5.1 Pro
5. Test Environment Curve:



Sample Configuration & Quantity Under Test:
Quantity: 1 (ONYX-174)

Test Result:
No problem was found after the humidity storage test.

Cold start and hot start test

Test Date: 05-15~16-2008

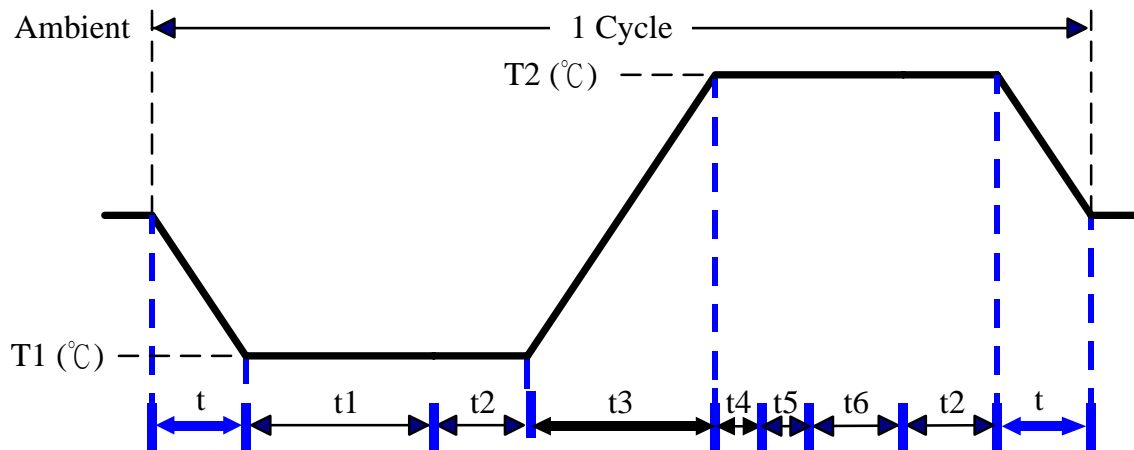
Test Product: ONYX-174

Test Site: AAEON QA Internal Lab.

Test Standard: Reference IEC 68-2-14 Testing procedures
Test N: Change of temperature Test

Test Equipment:
Programmable Temperature & Humidity Chamber
K.SON. INS. TECH. CORP.
Model: THS-D4H+-100
Date of Calibration: 05/12/08
Serial Number: 1241

Test Condition:



Parameters	Description
T1	-5°C
T2	45°C
t1	4 hrs
t2, t6	2 hrs
t4, t5	1hrs
t, t3	2°C/min
n (Cycle)	1

t = temprature slope
t , t1, t6: Power Off
t2: Power on/off test 10 times (on 2 min / off 5min)
t3, t4: Run PassMark Burn In Test
t5: Win XP Software restart test 3 times
Test Software: Windows XP

Test Result:

- a. No problem was found during the cold start test.
- b. No problem was found during the hot start test.